TOSHIBA Photocoupler GaAs Ired & Photo-Transistor

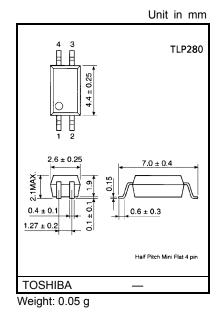
TLP280,TLP280-4

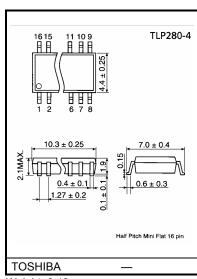
Programmable Controllers AC/DC–Input Module PC Card Modem (PCMCIA)

 $\rm TLP280$ and $\rm TLP280-4$ is a very small and thin coupler, suitable for surface mount assembly in applications such as PCMCIA fax modem, programmable controllers.

TLP280 and TLP280-4 consist of photo transistor, optically coupled to two gallium arsenide infrared emitting diode connected inverse parallel, and can operate directly by AC input current

- Collector-emitter voltage: 80 V (min)
- Current transfer ratio: 50% (min) Rank GB: 100% (min)
- Isolation voltage: 2500 Vrms (min)
- UL recognized: UL1577, file No. E67349
- BSI approved: BS EN 60065: 2002, BS EN 60950-1: 2002 Certificate No. 8143, 8144





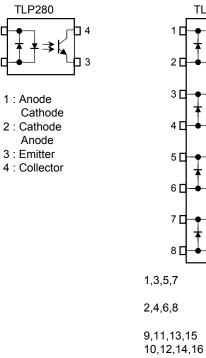
Weight: 0.19 g

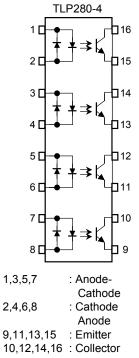
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Pin Configuration (top view)





Absolute Maximum Ratings (Ta = 25°C)

	Characteristic	Symbol	Ra	Unit		
	Characteristic	Symbol	TLP280	TLP280-4	Unit	
	Forward current	I _{F(RMS)}	±50		mA	
Ð	Forward current derating	ΔI _F /°C	–0.7 (Ta ≥ 53°C) –0.5 (Ta ≥ 25		mA /°C	
ш	Pulse forward current	IFP	±1 (100µs pı	А		
	Junction temperature	Тј	125		°C	
	Collector-emitter voltage	V _{CEO}	8	V		
	Emitter-collector voltage	V _{ECO}	-	V		
ъ	Collector current	IC	50		mA	
Detector	Collector power dissipation (1 circuit)	P _C	150	100	mW	
	Collector power dissipation derating (Ta ≥ 25°C) (1 circuit)	ΔP _C /°C	-1.5	-1.0	mW /°C	
	Junction temperature	Тј	125		°C	
Stor	rage temperature range	T _{stg}	-55	°C		
Ope	erating temperature range	T _{opr}	-55~100		°C	
Lea	d soldering temperature	T _{sol}	260 (10s)		°C	
Total package power dissipation (1 circuit)		PT	200 170		mW	
	al package power dissipation ating (Ta ≥ 25°C) (1 circuit)	ΔP _T /°C	-2.0 -1.7		mW /°C	
Isola	ation voltage (Note)	BVS	2500 (AC, 1min., R.H.≤ 60%)		Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note): Device considered a two terminal device: LED side pins shorted together and detector side pins shorted together.

Individual Electrical Characteristics (Ta = 25°C)

	Characteristic	Symbol	Test Condition	Min	Тур	Max	Unit
LED	Forward voltage	V _F	$I_F = \pm 10 \text{ mA}$	1.0	1.15	1.3	V
	Capacitance	CT	V = 0, f = 1 MHz	_	60	_	pF
Detector	Collector–emitter breakdown voltage	V(BR) CEO	I _C = 0.5 mA	80	_	_	V
	Emitter–collector breakdown voltage	V(BR) ECO	I _E = 0.1 mA	7	_	_	V
	Collector dark current (Note 1)	ICEO	V _{CE} = 48 V, Ambient light below (100 1x)	_	0.01 (2)	0.1 (10)	μA
			V _{CE} = 48 V, Ta = 85°C Ambient light below (100 1x)	_	2 (4)	50 (50)	μA
	Capacitance (collector to emitter)	C _{CE}	V = 0, f = 1 MHz	_	10	_	pF

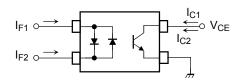
(Note 1): Because of the construction, leak current might be increased by ambient light. Please use photocoupler with less ambient light.

Coupled Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	MIn	Тур.	Max	Unit
Current transfer ratio	Ic / IF	I _F = ±5 mA, V _{CE} = 5 V Rank GB	50	—	600	%
	1C / 1F		100	—	600	
Saturated CTR	I _C / I _{F (sat)}	IF = ±1 mA, V _{CE} = 0.4 V Rank GB		60	—	%
			30	_	_	
	V _{CE (sat)}	I _C = 2.4 mA, I _F = ±8 mA	—	—	0.4	
Collector–emitter saturation voltage		I_{C} = 0.2 mA, I_{F} = ±1 mA Rank GB	_	0.2	_	V
ő			_	_	0.4	
Off-state collector current	I _{C(off)}	V _F = ± 0.7 V, V _{CE} = 48 V	_	_	10	μA
CTR symmetry	I _{C (ratio)}	$I_{C} (I_{F} = -5 \text{ mA}) / I_{C} (I_{F} = 5 \text{ mA})$ (Note 2)	0.33	—	3	—

(Note 2):

$$I_{C(ratio)} = \frac{I_{C2}(I_F = I_{F2}, V_{CE} = 5V)}{I_{C1}(I_F = I_{F1}, V_{CE} = 5V)}$$



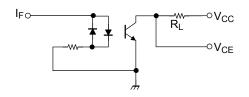
Isolation Characteristics (Ta = 25°C)

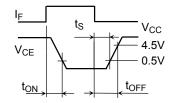
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Capacitance input to output	CS	V _S = 0V, f = 1 MHz	—	0.8	_	pF
Isolation resistance	R _S	V _S = 500 V, R.H.≤ 60%	5×10 ¹⁰	10 ¹⁴	_	Ω
	BVS	AC, 1 minute	2500	_	_	V
Isolation voltage		AC, 1 second, in oil	—	5000	_	V _{rms}
		DC, 1 minute, in oil	_	5000	_	V _{dc}

Switching Characteristics (Ta = 25°C)

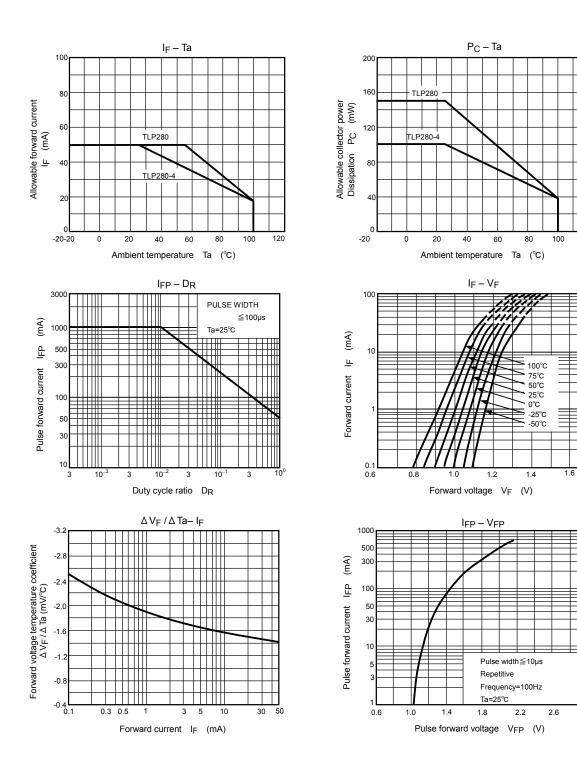
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Rise time	tr		_	2	_	
Fall time	t _f	V _{CC} = 10 V, I _C = 2 mA	_	3	_	μs
Turn–on time	t _{on}	$R_L = 100\Omega$	_	3	_	
Turn-off time	t _{off}		_	3	_	
Turn–on time	t _{ON}		_	2	_	
Storage time	ts	$R_L = 1.9 kΩ$ (Fig.1) V _{CC} = 5 V, I _F = ±16 mA	_	25	_	μs
Turn-off time	tOFF		_	40	_	

(Fig. 1): Switching time test circuit

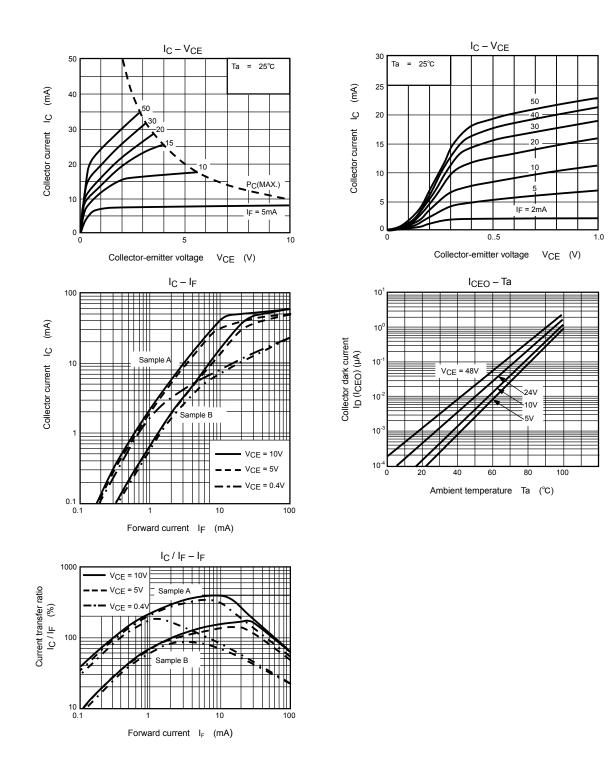




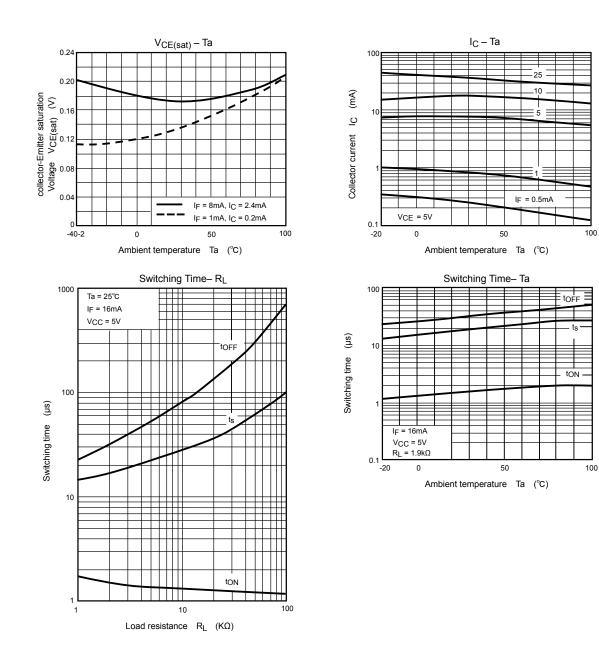
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